

EL896635818US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Yuan-Ku LAN)
Serial No.: Not yet assigned)
Filed: Concurrently herewith) Our Ref: B-4514 619559-4
For: "METHOD OF CHECKING OVERLAP)
ACCURACY OF PATTERNS ON FOUR)
STACKED SEMICONDUCTOR LAYERS") Date: February 28, 2002

JC997 U.S. PTO
10/086928
02/28/02

CLAIM TO PRIORITY UNDER 35 U.S.C. 119

Commissioner of Patents and Trademarks
Box New Patent Application
Washington, D.C. 20231

Sir:

[X] Applicant hereby makes a right of priority claim under 35
U.S.C. 119 for the benefit of the filing date(s) of the
following corresponding foreign application(s):

<u>COUNTRY</u>	<u>FILING DATE</u>	<u>SERIAL NUMBER</u>
Taiwan, R.O.C.	4 September 2001	90121880

- [] A certified copy of each of the above-noted patent
application was filed with the Parent Application
No. _____.
- [] To support applicants' claim, a certified copy of the above-
identified foreign patent application is enclosed herewith.
- [X] The priority document will be forwarded to the Patent Office
when required or prior to issuance.

Respectfully submitted,


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